	REVISIONS								
LTR	DESCRIPTION	DATE	APPROVED						
2	Page 10, figure 4, dimension t _f and t, are measured from 10% point. Drawing code ident. number changed to 67268. Page 2, correct generic part number. Editorial changes throughout.	6 OCT 1987	RfEvans						

REV PAGE Α REV **REV STATUS** OF PAGES PAGES 10 11 5 ITARY DRAWING PREPARED **Defense Electronics** This drawing is available for use by **Supply Center** all Departments and Agencies of the BY Dayton, Ohio Department of Defense TITLE: MICROCIRCUIT, DIGITAL, BIPOLAR, NINE-INPUT PARITY CHECKER/GENERATOR, MONOLITHIC SILICON Original date of drawing: DWG NO. 1 April 1987 CODE IDENT. NO. SIZE 5962-87543

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5962-E594

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

DESC FORM 193

MAY 86

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REV

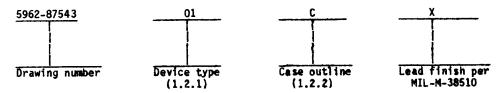
AMSC N/A

CURRENT CAGE CODE 67268



1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type Generic number Circuit function

01 82S62 Nine-input parity checker/generator

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter

Case outline

C D-1 (14-lead 1/4" x 3/4"), dual-in-line package Dp 4
F-2 (14-lead 1/4" x 3/8"), flat package Pp 4
F-2 (14-lead 1/4" x 3/8")

1.3 Absolute maximum ratings.

```
-0.5 V dc to +7.0 V dc
Supply voltage range - - - - - - - - -
Input voltage range- - - - - - - - - -
                                                  -1.5 V dc to +7.0 V dc
Storage temperature range - - - - - Maximum power dissipation (P_D) \frac{1}{2} - - - Lead temperature (soldering 10 seconds) - -
                                                   -65°C to +150°C
                                                  918.5 mW
+300°C
Thermal resistance, junction-to-case (0JC):
 25°C/W
30°C/W
Junction temperature (T<sub>J</sub>)-------
                                                   +175°C
DC input current - - - - - - - - - - -
                                                  -30 mA to +5.0 mA
DC output current, into output - - - - - -
                                                  +30 mA
```

1.4 Recommended operating conditions.

1/ Must withstand the added PD due to short circuit test (e.g., I_{OS}).

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2. APPLICABLE DOCUMENTS

2.1 <u>Government specification and standard</u>. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - 3. REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
 - 3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.
 - 3.2.4 <u>Case outlines</u>. The case outlines shall be in accordance with 1.2.2 herein.
 - 3.2.5 Switching waveforms. The switching waveforms shall be as specified on figure 4.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended ambient operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

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	1			1.	LT	mits	
Test Symbol Conditions $-55^{\circ}\text{C} < T_{A} < +125^{\circ}\text{C}$ Unless otherwise specifies			litions A < +125°C rwise specified	Group A subgroups	Min	Max	Unit
ligh level output level	V _{OH}	$V_{CC} = +4.5 \text{ V}$ $I_{OH} = -1 \text{ mA}$ $V_{IN} = 0.8 \text{ V or}$	2.0 V	1,2,3	2.5		٧
ow level output level	V _{OL}	VCC = +4.5 V IOL = 20 mA VIN = 0.8 V or	2.0 V	1,2,3		0.50	٧
Input clamp voltage	VIC	V _{CC} = +4.5 V I _{IH} = -18 mA		1,2,3		-1.2	٧
High level input current	I _{IH1}	V _{CC} = +5.5 V V _{IN} = 4.5 V		1,2,3	<u> </u>	10	 μ Α
	I _{1H2}	V _{CC} = +5.5 V V _{IN} = 5.5 V		1,2,3		1.0	mA
Low level input current	IIL	V _{CC} = +5.5 V V _{IN} = 0.5 V	P9 input	1,2,3		-0.4	mA
			All others inputs	1,2,3		-0.8	i mA
Output short circuit current	Ios	V _{CC} = +5.5 V	1/	1,2,3	-40	 -100 	mA
Supply current	Icc	V _{CC} = +5.5 V All inputs = G	Both outputs open ND, Inhibit = 4.5 V	1,2,3	 	67	mA
Functional testing		See 4.3.1c		7,8,			

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			• • •		Lin	nits	Mada
Test	Symbol	Cond -55°C < T; Unless othe	itions A < +125°C erwise specified	Group A subgroups	Min	Max	Unit
Propagation delay from P1 through P8 to even output	t _{PLH1}	CL 15 pF RL = 280Ω (see figure 4)	<u>2</u> /	9		23	ns
	1	<u> </u>	<u>3</u> /	9,10,11		28	!
	t _{PHL1}	1	 <u>2</u> / 	9		23	ns
	\ 	<u> </u> 	<u>3</u> /	9,10,11		28	1
Propagation delay from P1 through P8 to odd output	t _{PLH2}		<u>2</u> /	9	 	28	ns
	1		3/	9,10,11		35	
	tPHL2		<u>2</u> /	9		28	ns
		1	<u>3</u> /	9,10,11	; 	35	
to even output	t _{PLH3}		2/	9		12	ns
			<u>3</u> /	9,10,11	! !	15	
	t _{PHL3}		2/	9		12	ns
		<u> </u> 	3/	9,10,11	1	15	
Propagation delay from P9 to odd output	t _{PLH4}		2/	9		18	ns
		 	<u>3</u> /	9,10,11		22	
	t _{PHL} 4		2/	9		18	ns
			3/	9,10,11		22	<u> </u>
See footnotes at end of table	· .				···		
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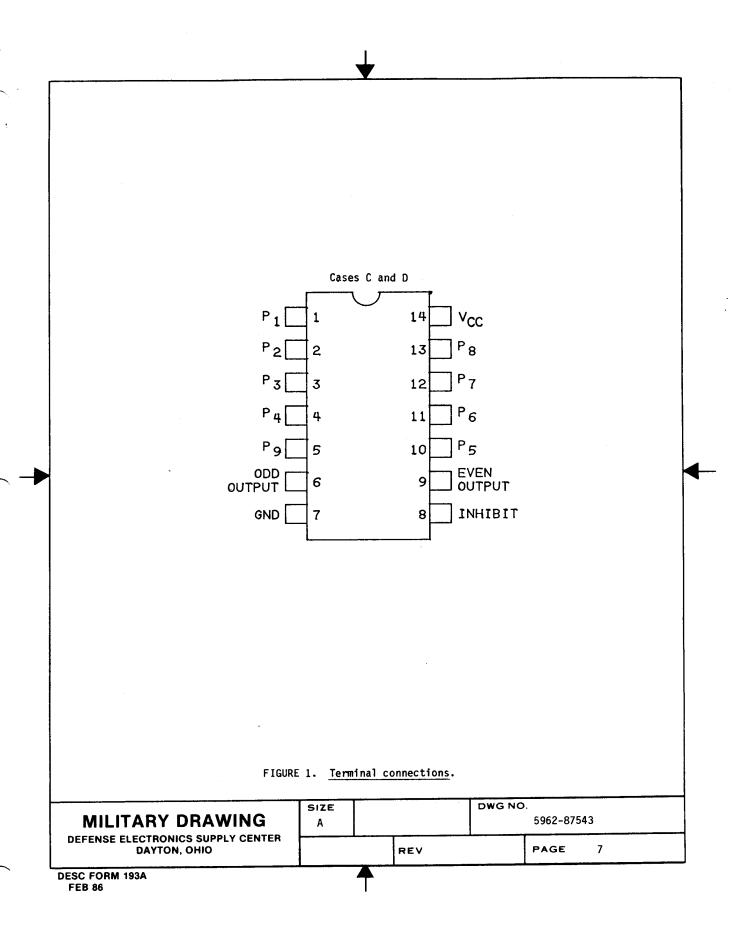
TABLE I.	<u>Electri</u>	cal performance o	characteristics - (Continued.			
Test	 Symbol	Cond	Group A subgroups	Limits		Unit	
		-55°C < T Unless oth	Conditions $-55^{\circ}C < T_A < +125^{\circ}C$ Unless otherwise specified			Max	
Propagation delay from inhibit to even output	t _{PLH5}		<u>2</u> /	9		9	ns
	1	1	 <u>3</u> / 	9,10,11		11	
	t _{PHL5}	† !	2/	9		9	ns
	}) 	<u>3</u> /	9,10,11		11	
Propagation delay from inhibit to odd output	tpLH6	T ! !	<u>2</u> /	9		 9 	l l ns l
			<u>3</u> /	9,10,11	 	11	f
	t _{PHL6}	- † 	2/	9		9	ns
			3/	9,10,11		11	1

Not more than one output should be shorted at a time, and the duration of the short circuit condition should not exceed one second.

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 $^{2/}V_{CC} = 5.0 V.$

^{3/} V_{CC} = +4.5 V to +5.5 V.

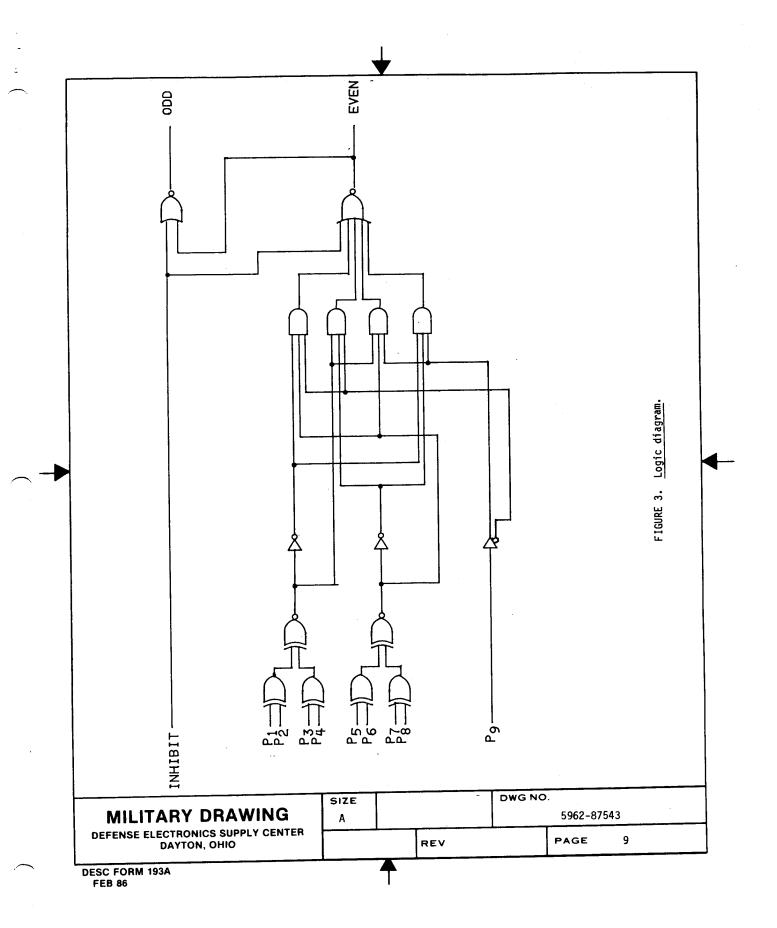


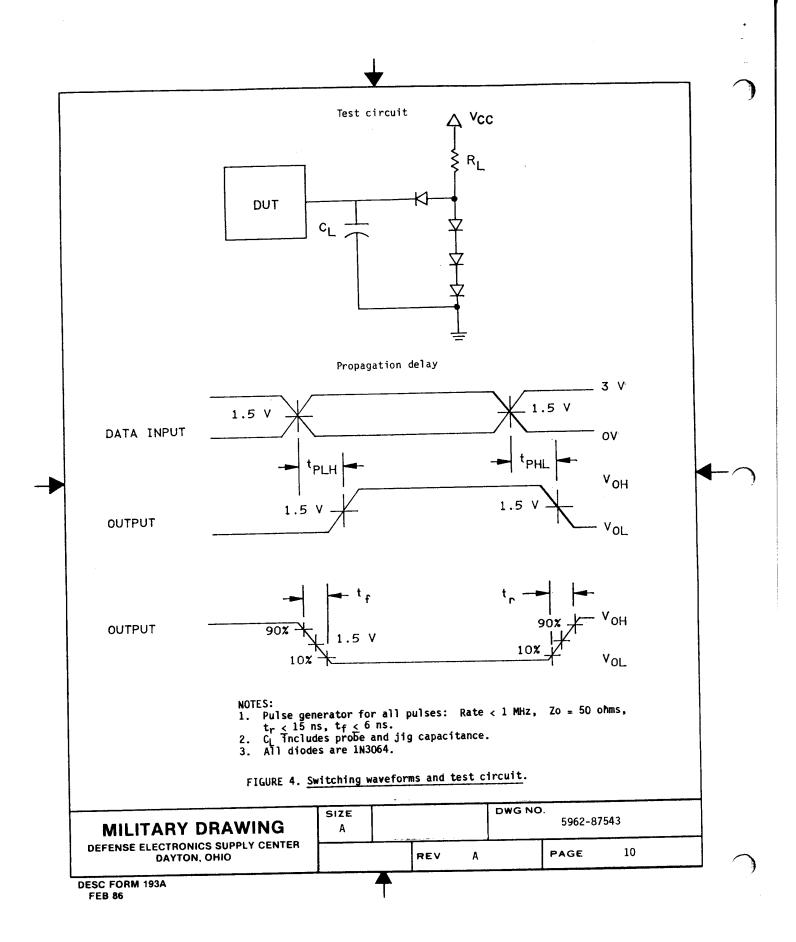
Output Number of P inputs Inhibit 0dd Even High Low 0 8 7 Н 1 2 3 Н Н 6 5 4 3 2 L Н 5 L Н Н 67 L Н H 8 L Χ L Н Χ

H = High L = Low X = Don't care

FIGURE 2. Truth table.

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- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 <u>Verification and review.</u> DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test (method 1015 of MIL-STD-883).
 - (1) Test condition C or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-SID-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroups 7 and 8 tests shall verify the truth table.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
 - (1) Test condition C or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	
	1*, 2, 3, 7, 8, 19, 10, 11
Group A test requirements (method 5005)	1, 2, 3, 7, 8, 19, 10**, 11**
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

PDA applies to subgroup 1. Subgroups 10 and 11, if not tested shall be guaranteed to the limits specified in table I.

5. PACKAGING

- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
- 6. NOTES
- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

 Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1</u> /
5962-8754301CX	34335	 S82S62/BCA
5962-8754301DX	34335	 S82S62/BDA

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number 34335 Vendor name and address

Advanced Micro Devices, Inc. 901 Thompson Place P.O. Box 3453 Sunnyvale, CA 94088

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